Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10632499	OLSCHEWSKI, FRANK
Examiner	Art Unit
Dennis Rosario	2624

SEARCHED					
Class	Subclass	Date	Examiner		
382	103	3/6/08	DR		
348	169	3/6/08	DR		
382	103 updated	9/2/08	DR		

SEARCH NOTES			
Search Notes	Date	Examiner	
East, all dB	3/6/08	DR	
ACM-+microscope +trajectory +vector-	3/6/08	DR	
IEEE- ((((microscope) <in>metadata)<and>((track*)<in>metadata))<and>((vector)< <n>metadata))-</n></and></in></and></in>	3/6/08	DR	
East, all db, updated	9/2/08	DR	
IEEE-((trajector* <near 5=""> pixel)<in>metadata)-</in></near>	9/2/08	DR	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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